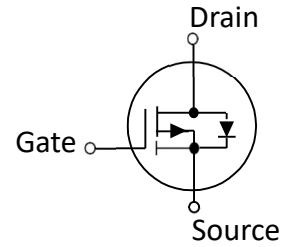


30V P-Channel MOSFET
SYMBOL

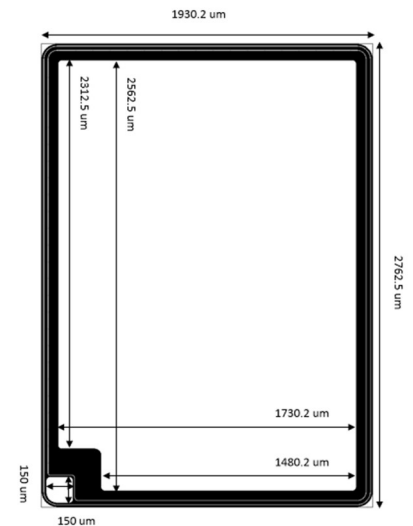
- Advanced Trench Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking


Electrical Characteristics in C/P Test (T_J at 25 °C)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Condition
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	-30	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
$R_{DS(ON)}$	Static Drain-Source On-Resistance	—	3.8	4.7	m Ω	$V_{GS} = 10V, I_D = -1A^{(2)}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance	—	6	7.5	m Ω	$V_{GS} = 4.5V, I_D = -1A^{(2)}$
$V_{GS(th)}$	Gate Threshold Voltage	-1	—	-2.5	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
I_{DSS}	Drain-to-Source Leakage Current	—	—	-1	μA	$V_{DS} = -30V, V_{GS} = 0V$
I_{GSS}	Gate-to-Source Leakage Current	-100	—	100	nA	$V_{DS} = 0V, V_{GS} = \pm 20V$
T_J, T_{STG}	Operating and Storage Temperature	-55°C to 150°C Max.				

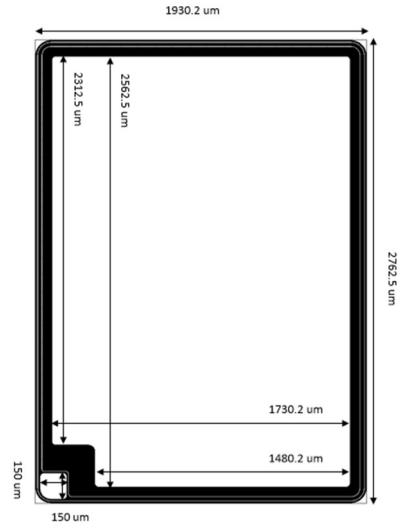
Mechanical Data
Die Drawing

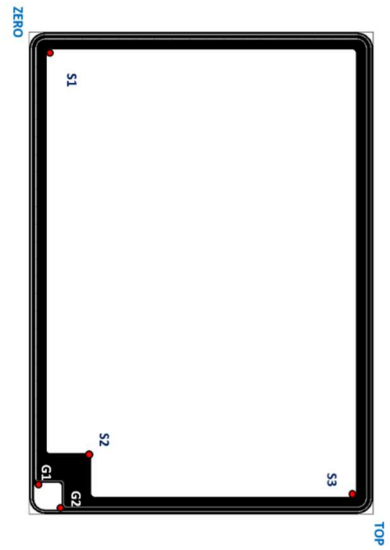
Chip Size	1930 μm X 2763 μm
Gate Pad Size	150 μm X 150 μm
Source Pad Size	1730 μm X 2563 μm
Scribe Line Width	60 μm
Wafer Thickness	150 μm
Wafer Diameter	200 mm
Gross Die	5081 EA
Source Metallization	Al-Cu (4 μm typical)
Drain Metallization	Ti-Ni-Ag
Passivation	SiN
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C \pm 3°C



(1) This characteristic assumes the die is assembled in SOP-8 package. Actual performance may degrade when assembled.

(2) Pulse Width $t_p = < 1$ mS, Duty Cycle $< 2\%$.

Specific Assembly Information Bill of Material (BOM)		Die Drawing
Package Type	DFN5*6	
Die Attach Method	Soft solder	
Soft Solder Composition	Pb,Sn,Ag	
Gate Wire Bonding	Cu, 2 mil x1	
Source Wire Bonding	Cu, 2 mil x8	
Molding Compound Manufacturer	G700HF	
Solder Plating Composition	Pure Tin	

Position			Bonding Diagram Top View
	X (um)	Y (um)	
ZERO	0	0	
TOP	2762.5	1930.2	
S1	100	100	
S2	2412.5	350	
S3	2662.5	1830.2	
G1	2584.65	31.15	
G2	2734.65	181.15	

Electrical Characteristics in F/T Test (T_J at 25 °C)						
Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	—	—	-1	μA	V _{DS} = -30V, V _{GS} = 0V
I _{GSSF}	Gate-to-Source Leakage Current	—	—	100	nA	V _{DS} = 0V, V _{GS} = +20V
I _{GSSR}	Gate-to-Source Leakage Current	—	—	-100	nA	V _{DS} = 0V, V _{GS} = -20V
BV _{DSS}	Drain-Source Breakdown Voltage	-30	—	—	V	V _{GS} = 0V, I _D = -250μA
BV _{DSS}	Drain-Source Breakdown Voltage	-30	—	—	V	V _{GS} = 0V, I _D = -1mA
R _{DS(ON)}	Static Drain-Source On-Resistance	—	—	6.5	mΩ	V _{GS} = -10V, I _D = -10A
V _{GS(th)}	Gate Threshold Voltage	-1	—	-2.5	V	V _{DS} = V _{GS} , I _D = -250μA
V _{SD}	Body Diode Forward Voltage	—	—	-1.2	V	V _{GS} = 0V, I _{SD} = -10A
I _{AS}	Avalanche Current				A	V _{DD} = 25V, V _{GS} = 10V, R _G = 25Ω, L = 0.5mH
T _J , T _{STG}	Operating and Storage Temperature	-55	—	150	°C	

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